

2N2381 (GERMANIUM)

2N2382



PNP germanium epitaxial mesa transistors for high-speed, high-current switching applications.

CASE 31 (TO-5)

Collector connected to case

MAXIMUM RATINGS

Rating	Symbol	2N2381	2N2382	Unit
Collector-Emitter Voltage	V_{CEO}	15	20	Vdc
Collector-Base Voltage	V_{CB}	30	45	Vdc
Emitter-Base Voltage	V_{EB}	4.0	4.0	Vdc
Collector Current-Continuous	I_C	500		mAdc
Total Device Dissipation @ $T_A = 25^\circ\text{C}$ Derate above 25°C	P_D	300	4.0	mW mW/ $^\circ\text{C}$
Total Device Dissipation @ $T_C = 25^\circ\text{C}$ Derate above 25°C	P_D	750	10	mW mW/ $^\circ\text{C}$
Operating and Storage Junction Temperature Range	T_J, T_{stg}	-65 to +100		$^\circ\text{C}$

FIGURE 1 — ACTIVE REGION TIME CONSTANT

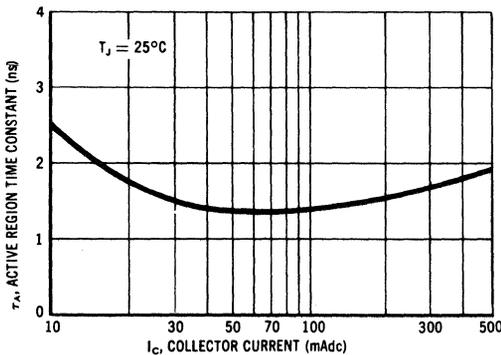
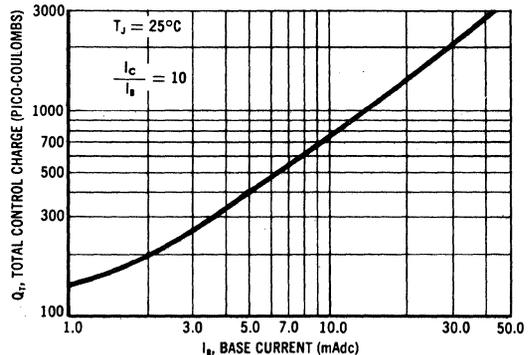


FIGURE 2 — TOTAL CONTROL CHARGE



2N2381, 2N2382 (Continued)

ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Fig. No.	Symbol	Min	Typ	Max	Unit
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OFF CHARACTERISTICS

Collector-Emitter Breakdown Voltage ($I_C = 10 \text{ mAdc}$, $I_E = 0$) 2N2381 2N2382		BV_{CEO}	15 20	- -	- -	Vdc
Collector-Base Breakdown Voltage ($I_C = 100 \mu\text{Adc}$, $I_E = 0$) 2N2381 2N2382		BV_{CBO}	30 45	- -	- -	Vdc
Latch-Up Voltage 2N2381 2N2382	7	LV_{CEX}	20 25	- -	- -	Vdc
Collector Cutoff Current ($V_{CE} = 30 \text{ Vdc}$, $V_{BE} = 0$) ($V_{CE} = 45 \text{ Vdc}$, $V_{BE} = 0$) 2N2381 2N2382		I_{CES}	- -	- -	100 100	μAdc
Collector Cutoff Current ($V_{CB} = 5 \text{ Vdc}$, $I_E = 0$) ($V_{CB} = 5 \text{ Vdc}$, $I_E = 0$, $T_A = 85^\circ\text{C}$) ($V_{CB} = 20 \text{ Vdc}$, $I_E = 0$) 2N2381 2N2382		I_{CBO}	- - -	1.0 - -	7.0 100 25 15	μAdc
Emitter Cutoff Current ($V_{BE} = 0.5 \text{ Vdc}$, $I_C = 0$) ($V_{BE} = 4 \text{ Vdc}$, $I_C = 0$)		I_{EBO}	- -	- -	0.005 1.0	mAdc

ON CHARACTERISTICS

DC Current Gain ($I_C = 200 \text{ mAdc}$, $V_{CE} = 0.5 \text{ Vdc}$) ($I_C = 400 \text{ mAdc}$, $V_{CE} = 1.0 \text{ Vdc}$)	11	h_{FE}	40 25	- -	- -	-
Collector-Emitter Saturation Voltage ($I_C = 200 \text{ mAdc}$, $I_B = 20 \text{ mAdc}$) ($I_C = 400 \text{ mAdc}$, $I_B = 40 \text{ mAdc}$)	8, 10	$V_{CE(sat)}$	- -	0.25 0.4	0.4 0.7	Vdc
Base-Emitter Saturation Voltage ($I_C = 200 \text{ mAdc}$, $I_B = 20 \text{ mAdc}$) ($I_C = 400 \text{ mAdc}$, $I_B = 40 \text{ mAdc}$)	9, 10	$V_{BE(sat)}$	0.45 -	0.54 0.71	0.7 0.9	Vdc

DYNAMIC CHARACTERISTICS

Current-Gain - Bandwidth Product ($I_C = 20 \text{ mAdc}$, $V_{CE} = 10 \text{ Vdc}$, $f = 100 \text{ MHz}$)		f_T	300	-	-	MHz
Output Capacitance ($V_{CB} = 10 \text{ Vdc}$, $I_E = 0$, $f = 4 \text{ MHz}$)	13	C_{ob}	-	3.5	6.0	pF
Input Capacitance ($V_{BE} = 1 \text{ Vdc}$, $I_C = 0$, $f = 4 \text{ MHz}$)	13	C_{ib}	-	8.0	15	pF
Delay Time	4	t_d	-	4.5	7.0	ns
Rise Time	4	t_r	-	8.0	15	ns
Storage Time	3, 4	t_s	-	20	30	ns
Fall Time	4	t_f	-	8.0	15	ns
Active Region Time Constant	1, 4	τ_A	-	1.6	3.0	ns

FIGURE 3 — STORAGE TIME VARIATIONS

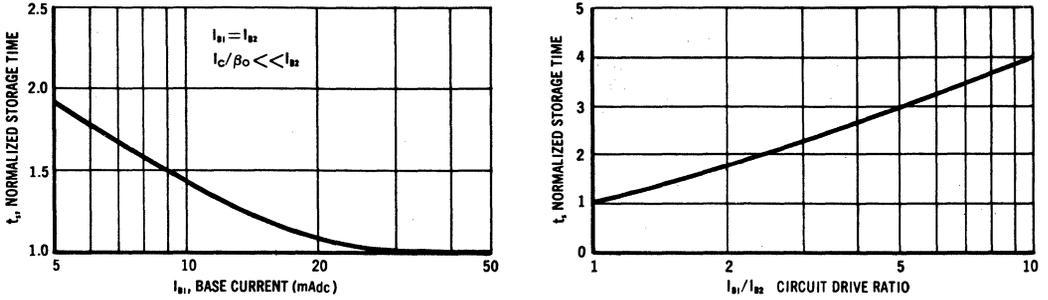


FIGURE 4 — SWITCHING TIME EQUATIONS & TEST CIRCUIT

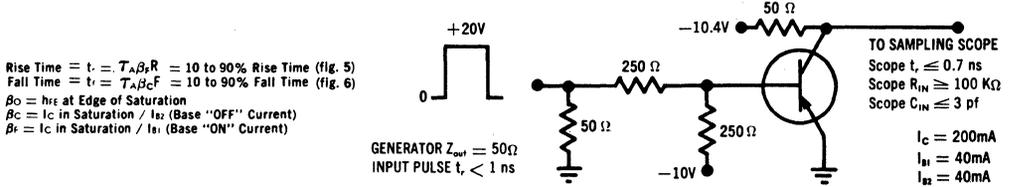


FIGURE 5 — RISE TIME FACTOR

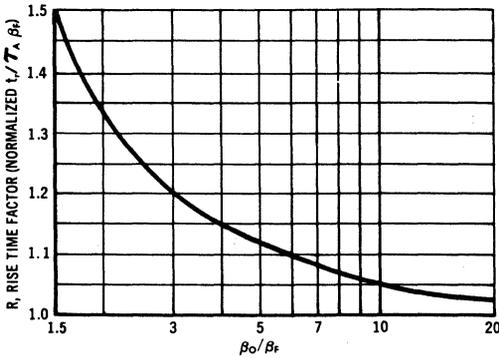


FIGURE 6 — FALL TIME FACTOR

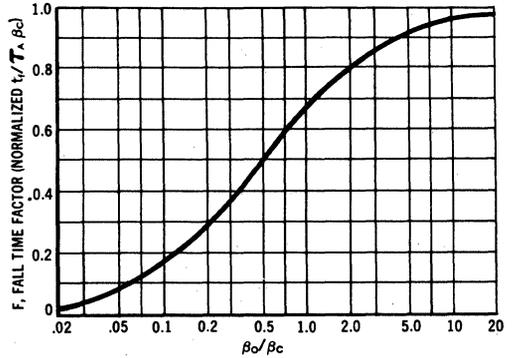


FIGURE 7 — COLLECTOR LATCH-UP VOLTAGE AND TEST CIRCUIT

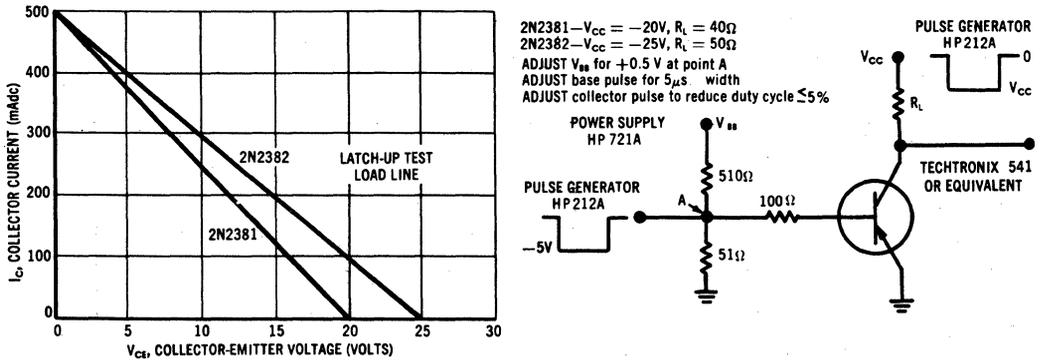


FIGURE 8 — COLLECTOR-EMITTER SATURATION VOLTAGES versus BASE CURRENT

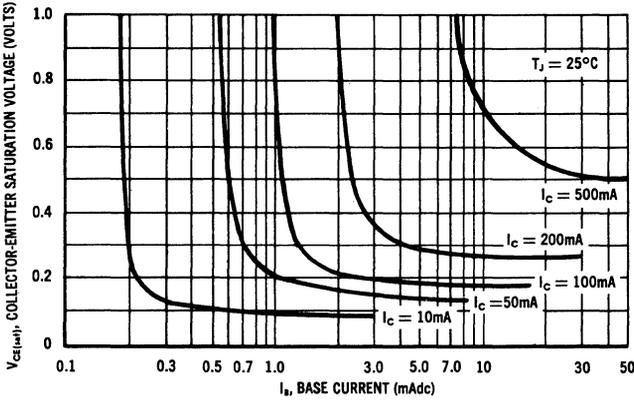


FIGURE 9 — BASE-EMITTER VOLTAGE versus COLLECTOR CURRENT

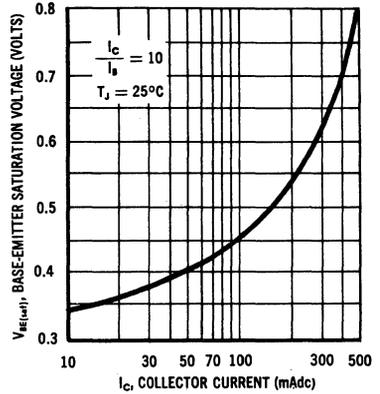


FIGURE 10 — TEMPERATURE COEFFICIENTS

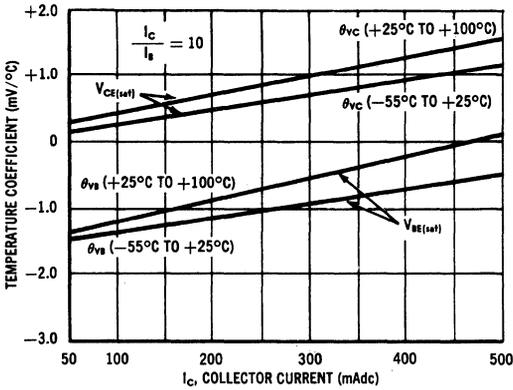


FIGURE 11 — NORMALIZED GAIN CHARACTERISTICS

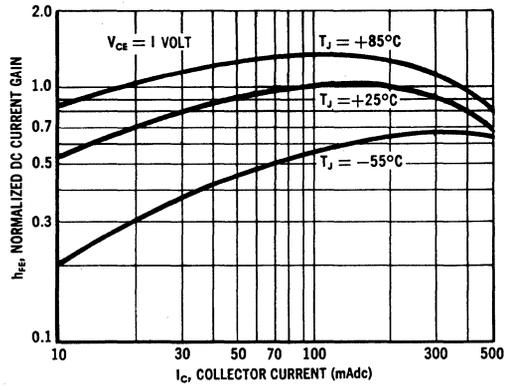


FIGURE 12 — LEAKAGE CHARACTERISTICS COMMON EMITTER

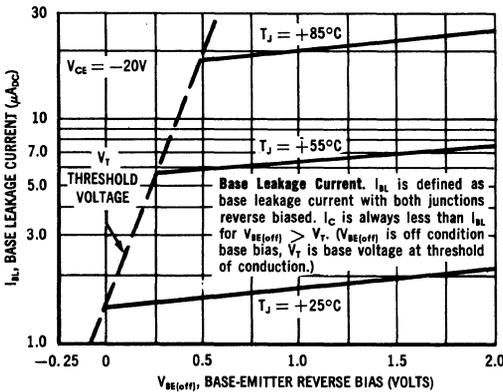


FIGURE 13 — JUNCTION CAPACITANCE versus REVERSE VOLTAGE

